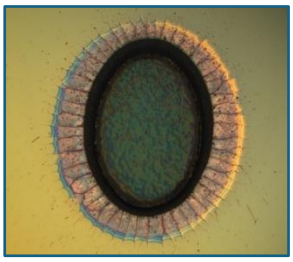
Characterization of Optical Parameters



Method	λ [nm]	τ	Note
Laser-induced damage			
	266	5 ns	≤ 100 Hz
	355	5 ns	≤ 100 Hz
	532	6 ns	≤ 100 Hz
	1030	cw	
	1030	170 fs	≤ 1 MHz
	1064	8 ns	≤ 100 Hz
Absorption			
	193	15 ns	≥ 70 ppm
	355	quasi cw	≥ 7 ppm
	532	quasi cw	≥ 1 ppm
	1064	quasi cw	≥ 0.1 ppm
	10600	quasi cw	
Cavity-Ring-Down			
	532		AOI 0°, 30°
	1064		45°
Scattering			
Total Scattering	532		≥1 ppm
Spectroscopy			
VUV/DUV	120-230		
	155-300		
UV/VIS/IR	200-1500		
IR	1000-25000		
Durability Test			
Abrasion, Humidity, Heat, Stripping, etc.			
R- & T-measurement			
	1030		
	1064		
	10600		
Further setups			
Zygo Verifire XPZ	633		
Homogenity/Uniformity	400 - 950		70 x 60 cm
EDX, SEM, OCT, SLOT, NanoTom			

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